

FAIRCHILD SEMICONDUCTOR®

May 2009

FDMS6681Z

P-Channel PowerTrench® MOSFET

-30 V, -49 A, 3.2 m Ω

Features

- Max $r_{DS(on)}$ = 3.2 m Ω at V_{GS} = -10 V, I_D = -21.1 A
- Max $r_{DS(on)}$ = 5.0 m Ω at V_{GS} = -4.5 V, I_D = -15.7 A
- Advanced Package and Silicon combination for low r_{DS(on)}
- HBM ESD protection level of 8kV typical(note 3)
- MSL1 robust package design
- RoHS Compliant

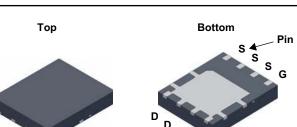
General Description

The FDMS6681Z has been designed to minimize losses in load switch applications. Advancements in both silicon and package technologies have been combined to offer the lowest $r_{DS(on)}$ and ESD protection.

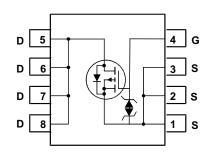
Applications

- Load Switch in Notebook and Server
- Notebook Battery Pack Power Management









MOSFET Maximum Ratings TA = 25 °C unless otherwise noted

| Symbol | Parameter | | | Ratings | Units |
|-----------------------------------|--|------------------------|-----------|-------------|-------|
| V _{DS} | Drain to Source Voltage | | | -30 | V |
| V_{GS} | Gate to Source Voltage | | | ±25 | V |
| | Drain Current -Continuous (Package limited) | T _C = 25 °C | | -49 | |
| | -Continuous (Silicon limited) | T _C = 25 °C | | -116 | A |
| I _D | -Continuous | T _A = 25 °C | (Note 1a) | -21.1 | 7 ^ |
| | -Pulsed | | | -90 | |
| Б | Power Dissipation | T _C = 25 °C | | 73 | W |
| P_{D} | Power Dissipation | T _A = 25 °C | (Note 1a) | 2.5 | |
| T _J , T _{STG} | Operating and Storage Junction Temperature Range | | | -55 to +150 | °C |

Thermal Characteristics

| $R_{\theta JC}$ | Thermal Resistance, Junction to Case | 1.7 | °C/W |
|-----------------|---|-----|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient (Note 1a) | 50 | C/VV |

Package Marking and Ordering Information

| Device Marking | Device | Package Reel Size Tape Wide | | Tape Width | Quantity |
|----------------|-----------|-----------------------------|--|------------|------------|
| FDMS6681Z | FDMS6681Z | Power 56 13 " | | 12 mm | 3000 units |

查询"FDMS6681Z"供应商 Electrical Characteristics $T_J = 25 \, ^{\circ}\text{C}$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|--|--|--|-----|-----|-----|-------|
| Off Chara | cteristics | | | | | |
| BV _{DSS} | Drain to Source Breakdown Voltage | $I_D = -250 \mu A, V_{GS} = 0 V$ | -30 | | | V |
| $\frac{\Delta BV_{DSS}}{\Delta T_{J}}$ | Breakdown Voltage Temperature Coefficient | I _D = -250 μA, referenced to 25 °C | | 20 | | mV/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} = -24 V, V _{GS} = 0 V | | | -1 | μА |
| I _{GSS} | Gate to Source Leakage Current | V _{GS} = ±25 V, V _{DS} = 0 V | | | ±10 | μА |

On Characteristics

| V _{GS(th)} | Gate to Source Threshold Voltage | $V_{GS} = V_{DS}, I_D = -250 \mu A$ | -1 | -1.7 | -3 | V |
|--|--|---|----|------|-----|-------|
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate to Source Threshold Voltage Temperature Coefficient | I _D = -250 μA, referenced to 25 °C | | -7 | | mV/°C |
| | | $V_{GS} = -10 \text{ V}, I_D = -22.1 \text{ A}$ | | 2.7 | 3.2 | |
| r _{DS(on)} | Static Drain to Source On Resistance | $V_{GS} = -4.5 \text{ V}, I_D = -15.7 \text{ A}$ | | 4.0 | 5.0 | mΩ |
| , , | | V_{GS} = -10 V, I_D = -22.1 A, T_J = 125 °C | | 3.9 | 5.0 | |
| 9 _{FS} | Forward Transconductance | V _{DD} = -10 V, I _D = -22.1 A | | 143 | | S |

Dynamic Characteristics

| C _{iss} | Input Capacitance | V - 45 V V - 0 V | 7803 | 10380 | pF |
|------------------|------------------------------|--|------|-------|----|
| C _{oss} | Output Capacitance | V _{DS} = -15 V, V _{GS} = 0 V, f = 1 MHz | 1540 | 2050 | pF |
| C _{rss} | Reverse Transfer Capacitance | 1 - 1 101112 | 1345 | 2020 | pF |

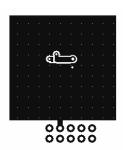
Switching Characteristics

| t _{d(on)} | Turn-On Delay Time | | | 15 | 24 | ns |
|---------------------|-------------------------------|---|--------------------------|-----|-----|----|
| t _r | Rise Time | V_{DD} = -15 V, I_{D} = -22.1 A, V_{GS} = -10 V, R_{GEN} = 6 Ω | | 38 | 61 | ns |
| t _{d(off)} | Turn-Off Delay Time | | | 260 | 416 | ns |
| t _f | Fall Time | | | 197 | 316 | ns |
| Qg | Total Gate Charge | V _{GS} = 0 V to -10 V | | 172 | 241 | nC |
| Qg | Total Gate Charge | V _{GS} = 0 V to -5 V | V _{DD} = -15 V, | 97 | 136 | nC |
| Q _{gs} | Gate to Source Charge | | I _D = -22.1 A | 22 | | nC |
| Q _{ad} | Gate to Drain "Miller" Charge | | | 46 | | nC |

Drain-Source Diode Characteristics

| V Source to Drain Diade Ferward Voltag | $V_{GS} = 0 \text{ V}, I_S = -2.1 \text{ A}$ (Note 2) | | 0.68 | 1.2 | V | |
|--|---|--|------|------|------|----|
| V _{SD} | V _{SD} Source to Drain Diode Forward Voltage | V _{GS} = 0 V, I _S = -22.1 A (Note 2) | | 0.79 | 1.25 | V |
| t _{rr} | Reverse Recovery Time | I _F = -22.1 A, di/dt = 100 A/μs | | 44 | 71 | ns |
| Q _{rr} | Reverse Recovery Charge | | | 39 | 63 | nC |

^{1.} R_{0JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. The diode connected between the gate and source servers only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

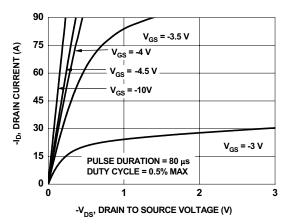


Figure 1. On Region Characteristics

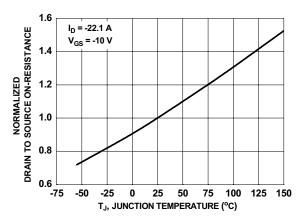


Figure 3. Normalized On Resistance vs Junction Temperature

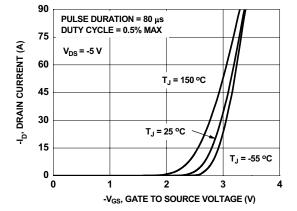


Figure 5. Transfer Characteristics

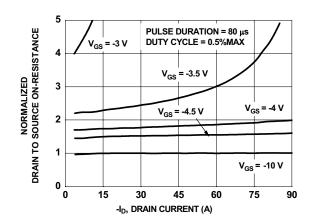


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

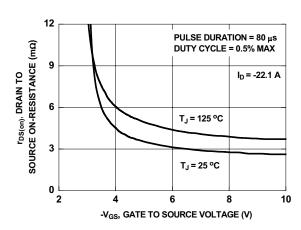


Figure 4. On-Resistance vs Gate to Source Voltage

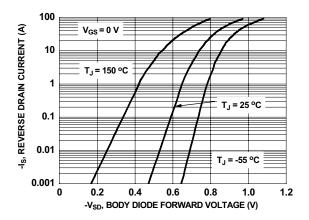


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted

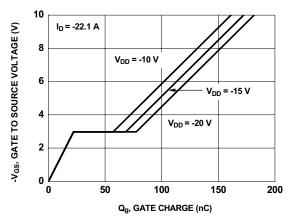


Figure 7. Gate Charge Characteristics

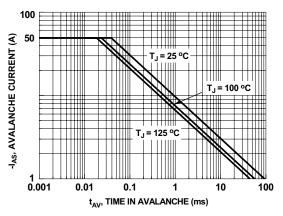


Figure 9. Unclamped Inductive Switching Capability

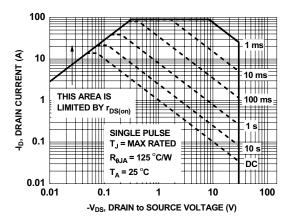


Figure 11. Forward Bias Safe Operating Area

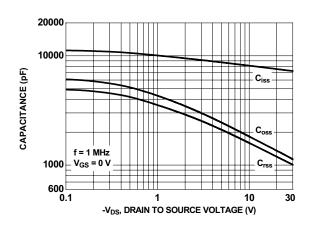


Figure 8. Capacitance vs Drain to Source Voltage

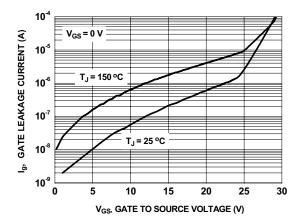


Figure 10. I_{gss} vs V_{gss}

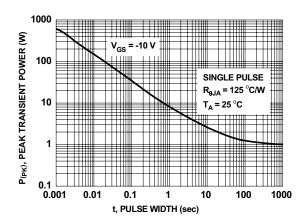


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25 °C unless otherwise noted

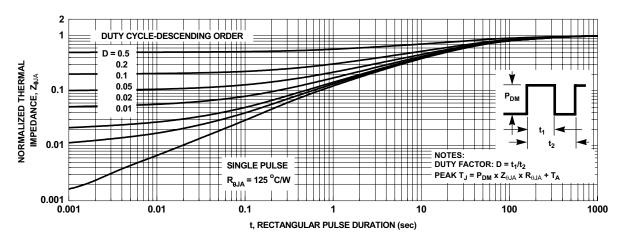
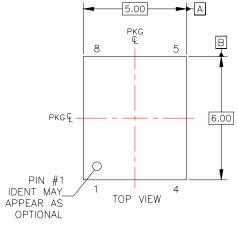
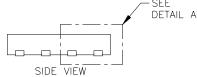
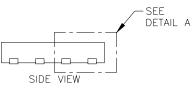


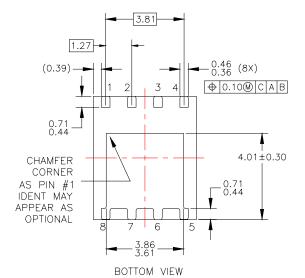
Figure 13. Junction-to-Ambient Transient Thermal Response Curve

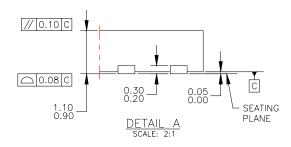
Dimensional Outline and Pad Layout

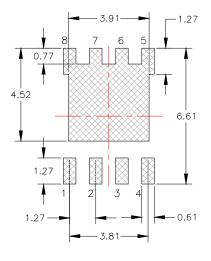




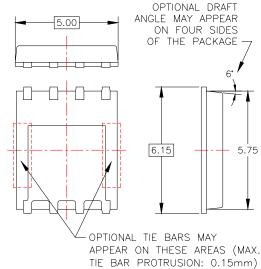








LAND PATTERN RECOMMENDATION



NOTES: UNLESS OTHERWISE SPECIFIED

- PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. AA, DATED OCTOBER 2002.
- DATED OCTOBER 2002.
 ALL DIMENSIONS ARE IN MILLIMETERS.
 DIMENSIONS DO NOT INCLUDE BURRS
 OR MOLD FLASH. MOLD FLASH OR
 BURRS DOES NOT EXCEED 0.10MM.
 DIMENSIONING AND TOLERANCING PER
 ASME Y14.5M-1994.
 DRAWING FILE NAME: POFNOBAREV4



SEMICONDUCTOR®

TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

Auto-SPM™ Build it Now™ CorePLUS™ CorePOWER™ CROSSVOLT™ CTL ™

Current Transfer Logic™ EcoSPARK® EfficentMax™ EZSWITCH™ '

Fairchild[®]

Fairchild Semiconductor® FACT Quiet Series™

FACT[®] FAST® FastvCore™ FETBench™

FlashWriter® * **FPSTM**

F-PFS™ FRFET®

Global Power ResourceSM Green FPS™

Green FPS™ e-Series™

Gmax™ GTO™ IntelliMAX™ ISOPLANAR™ MegaBuck™ MICROCOUPLER™ MicroFET™ MicroPak™ MillerDrive™ MotionMax™

Motion-SPM™ OPTOLOGIC® OPTOPLANAR®

PDP SPM™ Power-SPM™ PowerTrench® PowerXS™

Programmable Active Droop™

QFET' QSTM Quiet Series™ RapidConfigure[™]

Saving our world, 1mW /W /kW at a time™ SmartMax™

SMART START™ SPM® STEALTH™ SuperFET™ SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS™ SyncFET™ Sync-Lock™

SYSTEM ®* GENERAL

The Power Franchise® p wer franchise

TinyBoost™ TinyBuck™ TinyLogic[®] TINYOPTO™ TinyPower™ TinyPWM™ TinyWire™ TriÉault Detect™ TRUECURRENT™* μSerDes™

UHC® Ultra FRFET™ UniFET™ VCX™ VisualMax™

XSTM

*Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY
FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS **Definition of Terms**

| 20 | | |
|--------------------------|-----------------------|---|
| Datasheet Identification | Product Status | Definition |
| Advance Information | Formative / In Design | Datasheet contains the design specifications for product development. Specifications may change in any manner without notice. |
| Preliminary | First Production | Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design. |
| No Identification Needed | Full Production | Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design. |
| Obsolete | Not In Production | Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only. |

Rev. 140